

Search Notes

Application/Control No.

09/833,510

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2121

SEARCHED

Class	Subclass	Date	Examiner
455	3.05	5/12/2005	SC

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT, US_PGPUB, JPO, EPO, DERWENT, IBM_TDB)	5/12/2005	SC